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: June 30, 2017 : 2AL4MDMS-W1

RADIO TEST REPORT

Test Report No.: 11624584H-C

Applicant : **VAIO Corporation**

Type of Equipment Digital Music Score

Model No. DMS-W1

FCC ID 2AL4MDMS-W1

Test regulation FCC Part 15 Subpart C: 2017

*Bluetooth part

Test Result **Complied**

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The results in this report apply only to the sample tested.

This sample tested is in compliance with the above regulation.

The test results in this report are traceable to the national or international standards.

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This test report covers Radio technical requirements. It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)

> Date of test: April 17 to May 16, 2017

Representative test engineer:

Engineer

Consumer Technology Division

Approved by:

Takahiro Hatakeda

Leader

Consumer Technology Division



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REVISION HISTORY

Original Test Report No.: 11624584H-C

Revision	Test report No.	Date	Page revised	Contents
	11 (0 150 177 0	7 00 001=	revised	
- (Original)	11624584H-C	June 30, 2017	-	-
(= 8)				
			1	
			1	
			1	
			1	
			1	
			1	
			1	
			1	

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SECTION 1: Customer information

Company Name : VAIO Corporation

Address : 5432 Toyoshina, Azumino-shi, Nagano, 399-8282 Japan

Telephone Number : +81-263-50-7391 Facsimile Number : +81-263-50-7015 Contact Person : Masami Ogawa

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Digital Music Score

Model No. : DMS-W1

Serial No. : Refer to Section 4, Clause 4.2
Rating : DC 5.0 V (USB), DC 3.7 V (Battery)

Receipt Date of Sample : April 17, 2017

Country of Mass-production : Japan

Condition of EUT : Production prototype

(Not for Sale: This sample is equivalent to mass-produced items.)

Modification of EUT : No Modification by the test lab

2.2 Product Description

Model: DMS-W1 (referred to as the EUT in this report) is a Digital Music Score.

General Specification

Clock frequency(ies) in the system : 996 MHz, 630 MHz, 650 MHz, 528 MHz, 480 MHz, 26 MHz, 24 MHz,

32.768 kHz

Operating Temperature : +5 deg. C - +35 deg. C

Radio Specification

Radio Type : Transceiver

Power Supply (inner) : DC 1.8 V / DC 3.15 V

	IEEE802.11b	IEEE802.11g/n (20 M band)	IEEE802.11a/n (20 M band)	IEEE802.11n (40 M band)	Bluetooth Ver.3.0 with EDR function *1)
Frequency	2412	2412 MHz	5180 MHz -5240MHz	5190 MHz -5230MHz	2402 MHz -2480MHz
of operation	MHz-2462MHz	-2462MHz	5260 MHz -5320MHz	5270 MHz -5310MHz	
			5500 MHz -5580MHz	5510 MHz -5550 MHz	
			5660 MHz-5700 MHz	5670MHz *2)	
			*2)		FHSS (GFSK,
Type of modulation	DSSS (CCK, DQPSK, DBPSK)	OFDM-CCK (64QAM, 16QAM, QPSK, BPSK)	OFDM (64QAM, 16QAM	OFDM (64QAM, 16QAM, QPSK, BPSK)	
Channel spacing	5MHz		20MHz	40MHz	1MHz
Antenna type	monopole pattern ant	enna			
Antenna Gain	0.3 dBi		2.6 dBi		0.3 dBi
Antenna Connector	Surface mounted coar	xial connector			Surface mounted
type					coaxial connector

^{*1)} This test report applies for Bluetooth Ver3.0 with EDR function.

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^{*2) 5600} MHz-5650 MHz is not used.

^{*}Wireless LAN and Bluetooth do not transmit simultaneously.

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C

FCC Part 15 final revised on June 14, 2017 and effective July 14, 2017

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators

Section 15.207 Conducted limits

Section 15.247 Operation within the bands 902-928MHz,

2400-2483.5MHz, and 5725-5850MHz

* The revision on June 14, 2017, does not affect the test specification applied to the EUT.

* Also the EUT complies with FCC Part 15 Subpart B.

3.2 Procedures and results

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.10-2013 6. Standard test methods	FCC: Section 15.207	QP 17.1 dB, 0.15000 MHz, L AV	Complied	-
EIIIISSIOII	IC: RSS-Gen 8.8	IC: RSS-Gen 8.8	18.1 dB, 0.50660 MHz, N		
Carrier	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1)		G E I	
Frequency Separation	IC: -	IC: RSS-247 5.1 (b)	•	Complied	Conducted
20dB	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1)		Complied	Conducted
Bandwidth	IC: -	IC: RSS-247 5.1 (a)		•	
Number of	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1)(iii)	See data.	G 1: 1	0 1 1
Hopping Frequency	IC: -	IC: RSS-247 5.1 (d)		Complied	Conducted
Dwell time	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1)(iii)		Complied	Conducted
	IC: -	IC: RSS-247 5.1 (d)			
Maximum Peak	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(b)(1)		Complied	Conducted
Output Power	IC: RSS-Gen 6.12	IC: RSS-247 5.4 (b)		1	
Spurious	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(d)			Conducted/
Emission &	IC: RSS-Gen 6.13	IC: RSS-247 5.5	9.3dB 7206.000 MHz, AV, Vert.	Complied	Radiated (above 30 MHz)
Band Edge		RSS-Gen 8.9	1, 111, 1010		` ′
Compliance		RSS-Gen 8.10			*1)

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

FCC Part 15.31 (e)

This EUT provides stable voltage(DC 1.8 V/3.15 V) constantly to RF Part regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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^{*1)} Radiated test was selected over 30 MHz based on section 15.247(d).

^{*} In case any questions arise about test procedure, ANSI C63.10: 2013 is also referred.

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3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied	IC: RSS-Gen 6.6	IC: -	N/A	-	Conducted
Bandwidth					

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor k=2. Ise EMC Lab.

Antenna terminal test Uncertainty (+/-)							
Power meter Conducted emission and Power density Conducted emission							
Below	Above	Below	1 GHz -	3 GHz -	18 GHz -	26.5 GHz -	Channel power
1 GHz	1 GHz	1 GHz	3 GHz	18 GHz	26.5 GHz	40 GHz	
0.9 dB	1.0 dB	1.4 dB	1.5 dB	2.8 dB	2.8 dB	2.9 dB	2.6 dB

Frequency range	Conducted emission using AMN(LISN) (+/-)
0.009 MHz - 0.15 MHz	3.5 dB
0.15 MHz - 30 MHz	3.0 dB

	Radiated emission
Test distance	(+/-)
	9 kHz - 30 MHz
3 m	3.8 dB
10 m	3.7 dB

	Radiated emission (Below 1 GHz)				
Polarity	(3 m*) (+	/-)	(10 m*) (+/-)		
1 Olarity	30 MHz - 200 MHz	200 MHz -	30 MHz -	200 MHz -	
	30 M nz - 200 M nz	1000 MHz	200 MHz	1000 MHz	
Horizontal	5.0 dB	5.3 dB	5.0 dB	5.0 dB	
Vertical	4.7 dB	5.9 dB	5.0 dB	5.1 dB	

Radiated emission (Above 1 GHz)						
(3	m*) (+/-)	(1 m*) (+/-)		(10 m*) (+/-)		
1 GHz -	6 GHz -	10 GHz -	26.5 GHz -	1 GHz -		
6 GHz	18 GHz	26.5 GHz	40 GHz	18 GHz		
5.2 dB	5.4 dB	5.5 dB	5.5 dB	5.4 dB		

^{*}Measurement distance

 $\frac{Conducted\ Emission\ test}{The\ data\ listed\ in\ this\ test\ report\ has\ enough\ margin,\ more\ than\ the\ site\ margin.}$

Radiated emission test

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Ise EMC Lab. *NVLAP Lab. code: 200572-0 4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN Telephone: +81 596 24 8999, Facsimile: +81 596 24 8124

Test site	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms	M aximum measurement distance
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7	7.0 x 6.0	No.1 Power source room	10 m
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2	4.0 x 4.0	-	3 m
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9	6.8 x 5.75	No.3 Preparation room	3 m
No.3 shielded room	-	4.0 x 6.0 x 2.7	N/A	-	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9	6.8 x 5.75	No.4 Preparation room	3 m
No.4 shielded room	-	4.0 x 6.0 x 2.7	N/A	-	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9	6.0 x 6.0	-	-
No.6 shielded room	-	4.0 x 4.5 x 2.7	4.0 x 4.5	-	-
No.6 measurement room	-	4.75 x 5.4 x 3.0	4.75 x 4.15	-	-
No.7 shielded room	-	4.7 x 7.5 x 2.7	4.7 x 7.5	-	-
No.8 measurement room	-	3.1 x 5.0 x 2.7	N/A	-	-
No.9 measurement room	-	8.8 x 4.6 x 2.8	2.4 x 2.4	-	-
No.11 measurement room	-	6.2 x 4.7 x 3.0	4.8 x 4.6	-	-

^{*} Size of vertical conducting plane (for Conducted Emission test): 2.0 m x 2.0 m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

Refer to APPENDIX.

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SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9

Details of Operating Mode(s)

Test Item	Mode	Tested frequency
Conducted Emission,	Tx (Hopping Off) DH5, 3DH5	2402 MHz
Spurious Emission		2441 MHz
(Conducted/Radiated)		2480 MHz
Carrier Frequency Separation	Tx (Hopping On) DH5, 3DH5	2402 MHz
		2441 MHz
		2480 MHz
20dB Bandwidth	Tx (Hopping Off) DH5, 3DH5	2402 MHz
		2441 MHz
		2480 MHz
Number of Hopping Frequency	Tx (Hopping On) DH5, 3DH5	-
Dwell time	Tx (Hopping On),	-
	-DH1, DH3, DH5	
	-3DH1, 3DH3, 3DH5	
Maximum Peak Output Power	Tx (Hopping Off) DH5, 2DH5, 3DH5	2402 MHz
		2441 MHz
		2480 MHz
Band Edge Compliance	Tx DH5, 3DH5	2402 MHz
(Conducted)	-Hopping On	2480 MHz
	-Hopping Off	
99% Occupied Bandwidth	Tx DH5, 3DH5	2402 MHz
	-Hopping On	2441 MHz
	-Hopping Off	2480 MHz

^{*}As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)

Power settings: DH5: -0.8 dBm

2DH5/3DH5: -6.8 dBm

Software: MAC F/W version: Rev. 8.9.0.0.48

PHY F/W version: Rev. 8.2.0.0.232 (FDSP: 1.162)

*This setting of software is the worst case.

Any conditions under the normal use do not exceed the condition of setting.

In addition, end users cannot change the settings of the output power of the product.

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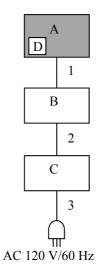
^{*2}DH mode (2Mb/s EDR: pi/4DQPSK) was excluded for other tests than power measurement by using 3DH mode (3 Mb/s EDR: 8DPSK) as a representative.

^{*} It is considered that the non-tested packet type (e.g. inquiry) can be omitted as it is complied with above all test items based on Bluetooth Core specification.

^{*}EUT has the power settings by the software as follows;

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4.2 Configuration and peripherals



^{*} Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remark
A	Digital Music Score	DMS-W1	38 *1), *2)	VAIO Corporation	EUT
			10 *3)		
В	Laptop PC	VJZ13AA11N	SKU013PVT1-S-06	VAIO Corporation	-
C	AC Adapter	VGP-AC19V74	1492510110002343	SONY	-
D	Micro SD Card	SDSDH-008G-J95	6356PKA053ES	SanDisk	-

List of cables used

DIDE O	i cubics useu				
No.	Name	Length (m)	Sh	ield	Remark
			Cable	Connector	
1	USB Cable	1.0 *1) 2.5 *2)	Shielded	Shielded	-
2	DC Cable	1.8	Unshielded	Unshielded	-
3	AC Cable	2.0	Unshielded	Unshielded	-

- *1) Used for Conducted emission
- *2) Used for Radiated emission
- *3) Used for Antenna terminal conducted tests

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SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The rear of tabletop was located 40 cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80 cm from any other grounded conducting surface. EUT was located 80 cm from a Line Impedance Stabilization Network (LISN) / Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30 cm to 40 cm long and were hanged at a 40 cm height to the ground plane. All unused 50 ohm connectors of the LISN (AMN) were resistivity terminated in 50 ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector : QP and CISPR AV
Measurement range : 0.15 MHz - 30 MHz

Test data : APPENDIX

Test result : Pass

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SECTION 6: Radiated Spurious Emission

Test Procedure

[For below 1 GHz]

EUT was placed on a urethane platform of nominal size, 0.5 m by 1.0 m, raised 0.8 m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

[For above 1 GHz]

EUT was placed on a urethane platform of nominal size, 0.5 m by 0.5 m, raised 1.5 m above the conducting ground plane.

The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with absorbent materials lined on a ground plane.

The height of the measuring antenna varied between 1 and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	30 MHz to 200 MHz	200 MHz to 1 GHz	Above 1 GHz
Antenna Type	Biconical	Logperiodic	Horn

In any 100 kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20~dBc was applied to the frequency over the limit of FCC 15.209 / Table 4 of RSS-Gen 8.9~(IC) and outside the restricted band of FCC 15.205 / Table 6 of RSS-Gen 8.10~(IC).

Frequency	Below 1 GHz	Above 1 GHz		20 dBc
Instrument used	Test Receiver	Spectrum Analyzer		Spectrum Analyzer
Detector	QP	PK	AV	PK
IF Bandwidth	BW 120 kHz	RBW: 1 MHz VBW: 3 MHz	RBW: 1 MHz VBW: 10 Hz *1)	RBW: 100 kHz VBW: 300 kHz
Test Distance	3 m	4.3 m*2) (1 GHz – 10 GHz), 1 m*3) (10 GHz – 26.5 GHz)		4.3 m*2) (1 GHz – 10 GHz), 1 m*3) (10 GHz – 26.5 GHz)

^{*1)} Although DA 00-705 accepts VBW = 10 Hz for AV measurements, it was confirmed that superfluous smoothing was not performed.

*2) Distance Factor: $20 \times \log (4.3 \text{ m/} 3.0 \text{ m}) = 3.13 \text{ dB}$ *3) Distance Factor: $20 \times \log (1.0 \text{ m/} 3.0 \text{ m}) = -9.5 \text{ dB}$

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 30 MHz - 26.5 GHz

Test data : APPENDIX
Test result : Pass

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SECTION 7: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	3 MHz	30 kHz	100 kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth *1)	Enough width to display emission skirts	1 to 5 % of OBW	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak Average *2)	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3 MHz	30 kHz	100 kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30 MHz	300 kHz	1 MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	100 kHz, 1 MHz	300 kHz, 3 MHz	As necessary capture the entire dwell time per hopping channel	Peak	Clear Write	Spectrum Analyzer
Conducted Spurious	9 kHz to 150 kHz	200 Hz	620 Hz	Auto	Peak	Max Hold	Spectrum Analyzer
Emission *3)	150 kHz to 30 MHz	9.1 kHz	27 kHz				
	30 MHz to 25 GHz	100 kHz	300 kHz	7			
Conducted Spurious Emission Band Edge compliance	10 MHz	100 kHz	300 kHz	Auto	Peak	Max Hold	Spectrum Analyzer

^{*1)} Peak hold was applied as Worst-case measurement.

Then, wide-band noise near the limit was checked separately, however the noise was not detected as shown in the chart. (9 kHz - 150 kHz; RBW = 200 Hz, 150 kHz - 30 MHz; RBW = 9.1 kHz)

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : APPENDIX

Test result : Pass

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^{*2)} Reference data

^{*3)} In the frequency range below 30MHz, RBW was narrowed to separate the noise contents.

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APPENDIX 1: Test data

Conducted Emission

DATA OF CONDUCTED EMISSION TEST

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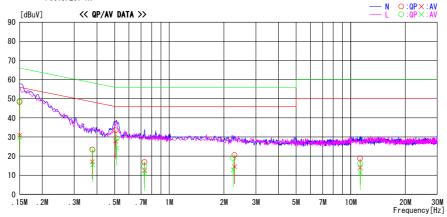
Temp./Humi. Engineer

Report No.

: 24 deg. C / 42 % RH : Hironobu Ohnishi

 ${\tt Mode / Remarks : Tx DH5 2441 MHz}$

LIMIT : FCC15. 207 QP FCC15. 207 AV



-	Reading	Level	Corr.	Resi	ılts	Lin	nit	Mar	gin		
Frequency	QP	AV	Factor	QP	AV	QP	AV	QP	AV	Phase	Comment
[MHz]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
0. 15000	35. 1	17. 7	13. 2	48. 3	30. 9	66. 0	56.0	17. 7	25. 1	N	
0. 37680	10. 3	3. 9	13. 2	23. 5		58. 3	48. 3	34. 8	31.2	N	
0. 50660	20. 2	14. 6	13.3	33. 5	27. 9	56.0	46.0	22. 5	18. 1	N	
0. 73145	3. 6	-0. 9	13.3	16. 9	12.4	56.0	46.0	39. 1	33.6	N	
2. 28935	7. 0	0.9	13.6	20. 6	14.5	56.0	46.0	35.4	31.5	N	
11. 26593	4. 4	-0. 3	14.3	18. 7	14.0	60.0	50.0	41.3	36.0	N	
0. 15000	35. 7	16.6	13. 2	48. 9	29.8	66. 0	56.0	17. 1	26. 2	L	
0. 37866	10. 1	2. 3	13. 2	23. 3	15.5	58. 3	48. 3	35.0	32.8	L	
0. 51370	16.0	10.9	13.3	29. 3	24. 2	56.0	46.0	26. 7	21.8	L	
0. 73000	1.5	-2.4	13.3	14. 8	10.9	56.0	46.0	41.2	35. 1	L	
2. 25300	5. 2	-0. 7	13.6	18. 8		56.0	46.0	37. 2	33. 1	L	
11. 28667	1. 7	-2. 9	14.3	16.0	11.4	60.0	50.0	44. 0	38. 6	L	

CHART: WITH FACTOR Peak hold data. CALCULATION: RESULT = READING + C.F (LISN + CABLE + ATTEN) Except for the above table: adequate margin data below the limits.

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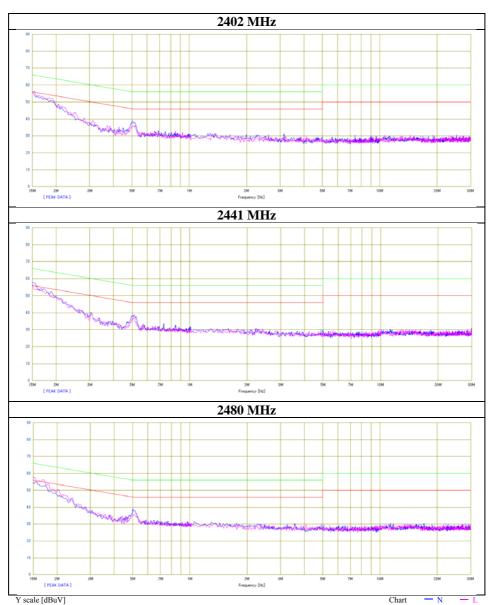
 Issued date
 : June 30, 2017

 FCC ID
 : 2AL4MDMS-W1

Conducted Emission

Test place Ise EMC Lab. No.2 Semi Anechoic Chamber

Report No. 11624584H
Date May 16, 2017
Temperature / Humidity 24 deg. C / 42 % RH
Engineer Hironobu Ohnishi
Mode Tx, Hopping Off, DH5



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Conducted Emission

DATA OF CONDUCTED EMISSION TEST

Ise EMC Lab. No.2 Semi Anechoic Chamber Date : 2017/05/16

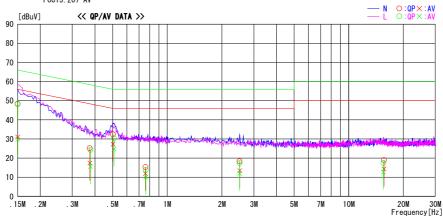
: 11624584H

Report No.

Temp./Humi. Engineer

: 24 deg. C / 42 % RH : Hironobu Ohnishi

Mode / Remarks : Tx 3DH5 2441 MHz



F	Reading	Level	Corr.	Resi	ults	Lin	nit	Mar	gin		
Frequency	QP	AV	Factor	QP	AV	QP	AV	QP	AV	Phase	Comment
[MHz]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
0. 15000	35. 1	17. 9	13. 2	48. 3		66. 0	56.0	17. 7	24. 9	N	
0. 37510	12.0	4. 2	13. 2	25. 2		58. 4	48. 4	33. 2	31.0	N	
0. 50265	19. 2	14. 0	13.3	32. 5	27. 3	56.0	46.0	23.5	18. 7	N	
0. 75900	2. 1	-1. 3	13.3	15. 4	12.0	56.0	46.0	40.6	34.0	N	
2. 50679	4. 8	-0. 2	13.6	18. 4	13. 4	56.0	46.0	37. 6	32.6	N	
15. 63085	4. 4	-0.3	14.6	19.0	14.3	60.0	50.0	41.0	35. 7	N	
0. 15000	35. 3	16. 7	13. 2	48. 5	29.9	66. 0	56.0	17. 5	26. 1	L	
0. 37800	11.1	2. 4	13. 2	24. 3	15. 6	58. 3	48. 3	34.0	32.7	L	
0.50910	17. 1	11.4	13. 3	30. 4	24. 7	56.0	46.0	25. 6	21.3	L	
0. 76190	0.5	-3. 3	13. 3	13. 8	10.0	56.0	46.0	42. 2	36.0	L	
2. 50679	3. 9	-1.6	13.6	17. 5	12.0	56.0	46.0	38. 5	34.0	L	
15. 53060	2. 9	-1. 9	14.6	17. 5	12. 7	60.0	50.0	42.5	37.3	L	

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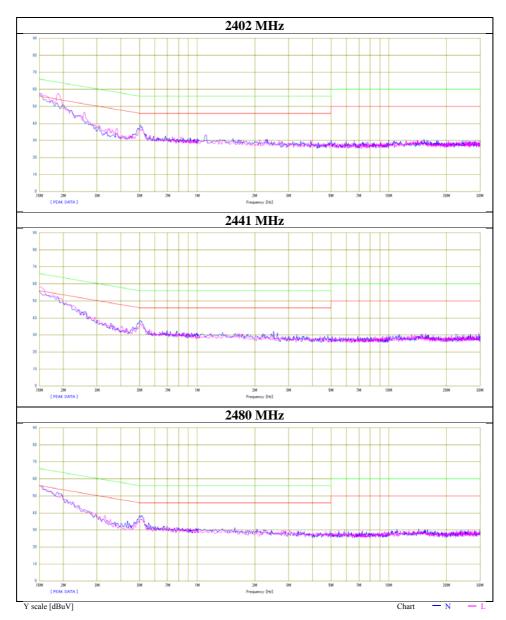
 Issued date
 : June 30, 2017

 FCC ID
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Conducted Emission

Test place Ise EMC Lab. No.2 Semi Anechoic Chamber

Report No. 11624584H
Date May 16, 2017
Temperature / Humidity 24 deg. C / 42 % RH
Engineer Hironobu Ohnishi
Mode Tx, Hopping Off, 3DH5



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 : 2AL4MDMS-W1

20dB Bandwidth and Carrier Frequency Separation

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H

Date May 8, 2017

Temperature / Humidity 24 deg. C / 41 % RH

Engineer Takumi Shimada

Mode Tx, Hopping Off, DH5

Mode	Freq.	20dB Bandwidth	Carrier Frequency	Limit for Carrier
			Separation	Frequency separation
	[MHz]	[MHz]	[MHz]	[MHz]
DH5	2402.0	0.913	1.000	>= 0.609
DH5	2441.0	0.811	1.000	>= 0.541
DH5	2480.0	0.811	1.000	>= 0.541
3DH5	2402.0	1.283	1.000	>= 0.855
3DH5	2441.0	1.286	1.000	>= 0.857
3DH5	2480.0	1.283	1.000	>= 0.855

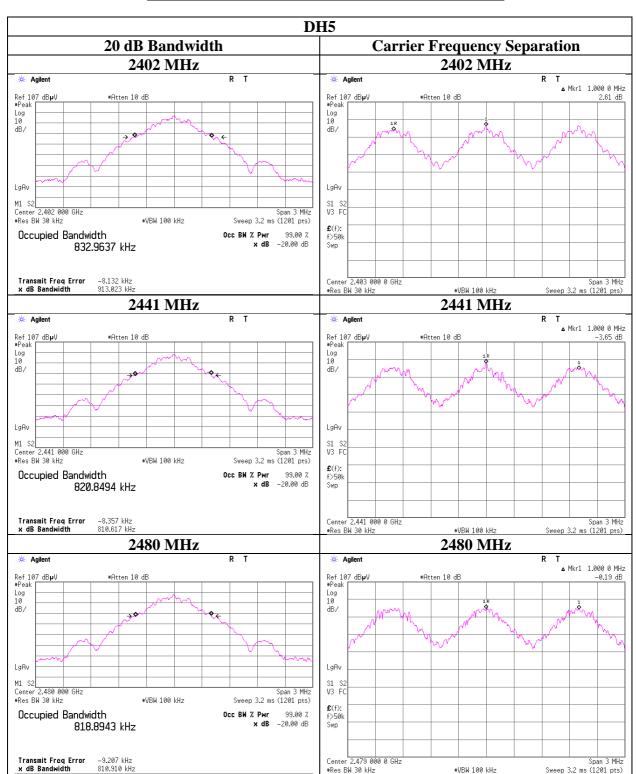
Limit: Two-thirds of 20dB Bandwidth or 25kHz (whichever is greater).

No limit applies to 20dB Bandwidth.

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20dB Bandwidth and Carrier Frequency Separation

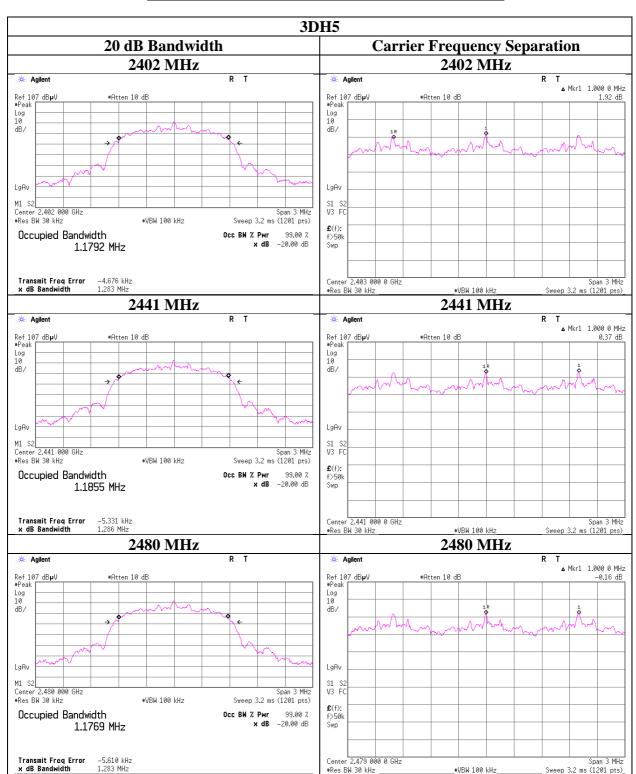


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20dB Bandwidth and Carrier Frequency Separation



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 FCC ID
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Number of Hopping Frequency

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date May 8, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping On

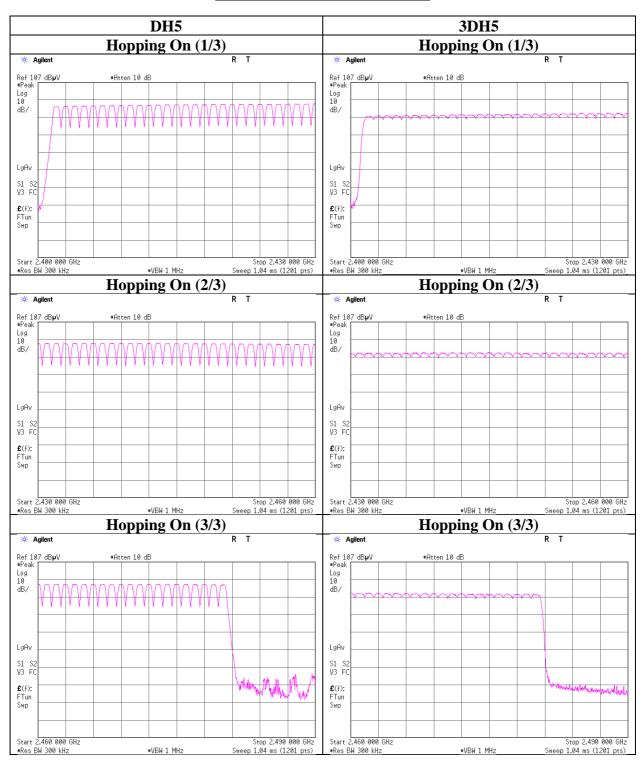
Mode	Number of channel	Limit
	[channels]	[channels]
DH5	79	>= 15
3DH5	79	>= 15

Test was not performed at AFH mode whose number of hopping channel is 20 channels because this Bluetooth radio is in compliance of Bluetooth Specification.

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Number of Hopping Frequency



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 FCC ID
 : 2AL4MDMS-W1

Dwell time

Test place Ise EMC Lab. No.11 Measurement Room

Report No. 11624584H
Date May 8, 2017
Temperature / Humidity 25 deg. C / 40 % RH
Engineer Takumi Shimada
Mode Tx, Hopping On

Mode	Number of transm		Length of	Result	Limit
	in a 31.6(79 Hopping	transmission			
	/ 12.8 (32 Hopping x 0.4)	[msec]	[msec]	[msec]	
DH1	50.0 times / 5 sec. x 31	.6 sec. = 316 times	0.419	132	400
DH3	24.6 times / 5 sec. x 31	.6 sec. = 156 times	1.677	262	400
DH5	19.6 times / 5 sec. x 31	.6 sec. = 124 times	2.927	363	400
3DH1	49.6 times / 5 sec. x 31	.6 sec. = 314 times	0.422	133	400
3DH3	23.6 times / 5 sec. x 31	.6 sec. = 150 times	1.680	252	400
3DH5	16.6 times / 5 sec. x 31	.6 sec. = 105 times	2.936	308	400

Sample Calculation

Result = Number of transmission x Length of transmission

*Average data of 5 tests.(except Inquiry)

Mode			Sampling [times]		Average				
	1	2	3	4	5	Average [times]				
DH1	50	50	50	50	50	50				
DH3	27	24	24	24	24	24.6				
DH5	17	21	20	17	23	19.6				
3DH1	49	49	50	50	50	49.6				
3DH3	21	24	24	23	26	23.6				
3DH5	13	21	15	14	20	16.6				

Sample Calculation

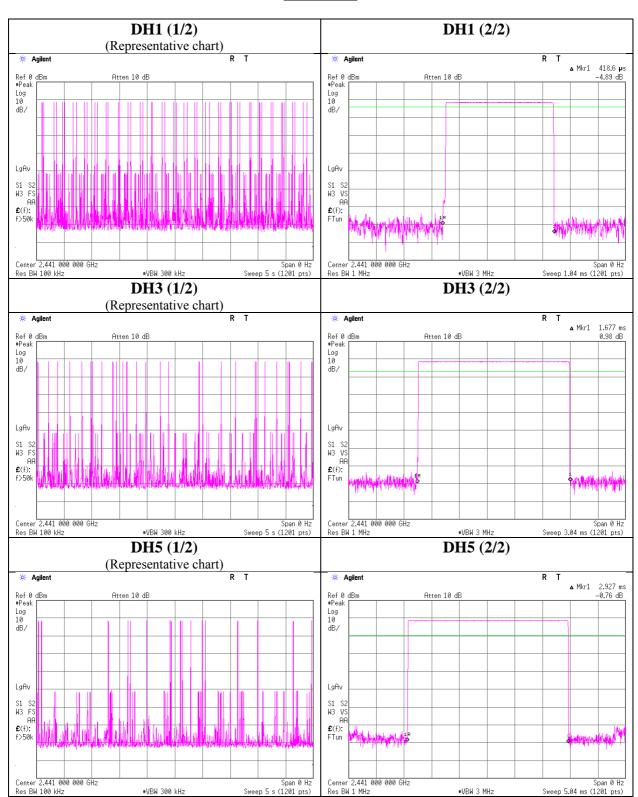
Average = Summation (Sampling 1 to 5) / 5

This device complies with the Bluetooth protocol for FHSS operation, employing a pseudo random channel selection and hopping rate to ensure that the occupancy time in N x 0.4s, where N is the number of channels being used in the hopping sequence ($20 \le N \le 79$), is always less than 0.4s regardless of packet size. This is confirmed in the test report for N = 79.

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Dwell time

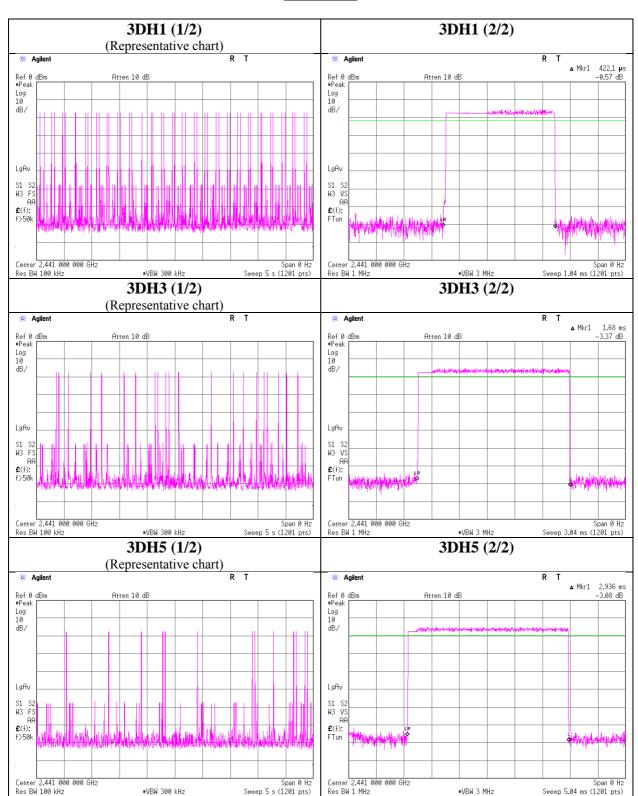


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Dwell time



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 FCC ID
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Maximum Peak Output Power

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date April 18, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping Off

Mode	Freq.	Reading	Cable	Atten.	Result		Limit		Margin
			Loss	Loss					
	[MHz]	[dBm]	[dB]	[dB]	[dBm]	[mW]	[dBm]	[mW]	[dB]
DH5	2402.0	-11.82	0.70	9.48	-1.64	0.69	20.96	125	22.60
DH5	2441.0	-10.25	0.70	9.48	-0.07	0.98	20.96	125	21.03
DH5	2480.0	-11.03	0.70	9.48	-0.85	0.82	20.96	125	21.81
2DH5	2402.0	-15.33	0.70	9.48	-5.15	0.31	20.96	125	26.11
2DH5	2441.0	-13.82	0.70	9.48	-3.64	0.43	20.96	125	24.60
2DH5	2480.0	-14.45	0.70	9.48	-4.27	0.37	20.96	125	25.23
3DH5	2402.0	-15.16	0.70	9.48	-4.98	0.32	20.96	125	25.94
3DH5	2441.0	-13.21	0.70	9.48	-3.03	0.50	20.96	125	23.99
3DH5	2480.0	-14.10	0.70	9.48	-3.92	0.41	20.96	125	24.88

Sample Calculation:

Result = Reading + Cable Loss (including the cable(s) customer supplied) + Attenuator Loss

Test was not performed at AFH mode, because the decrease of number of channel (min: 20ch) at AFH mode does not influence on the output power and bandwidth of the EUT.

As this device had AFH mode and frequency separation could not meet the requirement of over 20dB BW without 2/3 relaxation, 125mW power limit was applied to it.

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 : 2AL4MDMS-W1

<u>Average Output Power</u> (Reference data for SAR testing)

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date April 18, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping Off

Mode	Freq.	Reading	Cable	Atten.	Re	sult	Duty	Re	sult
			Loss	Loss	(Time a	verage)	factor	(Burst pow	er average)
	[MHz]	[dBm]	[dB]	[dB]	[dBm]	[mW]	[dB]	[dBm]	[mW]
DH5	2402.0	-12.04	0.70	9.48	-1.86	0.65	1.05	-0.81	0.83
DH5	2441.0	-11.78	0.70	9.48	-1.60	0.69	1.05	-0.55	0.88
DH5	2480.0	-12.82	0.70	9.48	-2.64	0.54	1.05	-1.59	0.69
2DH5	2402.0	-18.10	0.70	9.48	-7.92	0.16	1.05	-6.87	0.21
2DH5	2441.0	-17.91	0.70	9.48	-7.73	0.17	1.05	-6.68	0.21
2DH5	2480.0	-18.56	0.70	9.48	-8.38	0.15	1.05	-7.33	0.18
3DH5	2402.0	-18.12	0.70	9.48	-7.94	0.16	1.05	-6.89	0.20
3DH5	2441.0	-17.99	0.70	9.48	-7.81	0.17	1.05	-6.76	0.21
3DH5	2480.0	-18.63	0.70	9.48	-8.45	0.14	1.05	-7.40	0.18

Sample Calculation:

Result (Time average) = Reading + Cable Loss (including the cable(s) customer supplied) + Attenuator Loss Result (Burst power average) = Time average + Duty factor

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^{*}The equipment and cables were not used for factor 0 dB of the data sheets.

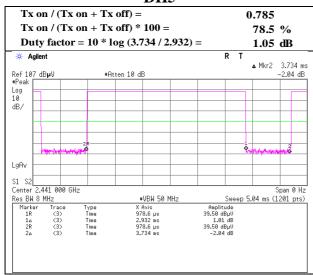
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Burst Rate Confirmation

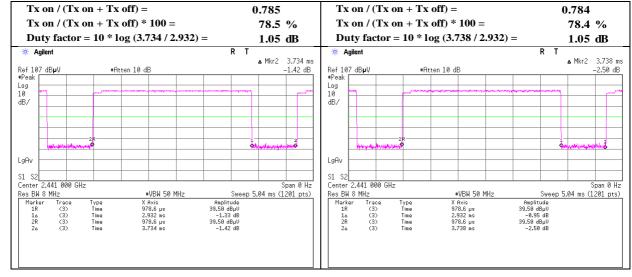
Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date April 18, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping Off

DH₅



2DH5 3DH5



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Radiated Spurious Emission

Report No. 11624584H Test place Ise EMC Lab.

Semi Anechoic Chamber No.3 No.4 No.4

Date April 17, 2017 April 22, 2017 April 23, 2017
Temperature / Humidity 21 deg. C / 59 % RH 21 deg. C / 41 % RH 19 deg. C / 37 % RH
Engineer Shuichi Ohyama Tomoki Matsui Tomoki Matsui (1 GHz -10 GHz) (Below 1 GHz) (Above 10 GHz)

Mode Tx, Hopping Off, DH5 2402 MHz

Polarity	Frequency	Detector	Reading	Ant.Fac.	Loss	Gain	Duty Factor	Result	Limit	Margin	Remark
	[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	
Hori	64.165	QP	35.1	6.8	7.8	32.1	-	17.6	40.0	22.4	
Hori	154.129	QP	36.0	15.2	8.7	32.0	-	27.9	43.5	15.6	
Hori	162.277	QP	36.1	15.6	8.8	32.0	-	28.5	43.5	15.0	
Hori	180.499	QP	32.0	16.3	9.0	32.0	-	25.3	43.5	18.2	
Hori	186.569	QP	32.3	16.3	9.0	32.0	-	25.6	43.5	17.9	
Hori	240.728	QP	39.3	11.6	9.5	31.9	-	28.5	46.0	17.5	
Hori	2390.000	PK	41.5	26.7	6.5	32.4	-	42.3	73.9	31.6	
Hori	4804.000	PK	38.3	31.0	8.7	31.4	-	46.6	73.9	27.3	Floor noise
Hori	7206.000	PK	39.3	35.7	10.0	32.1	-	52.9	73.9	21.0	Floor noise
Hori	9608.000	PK	39.4	37.2	10.6	32.9	-	54.3	73.9	19.6	Floor noise
Hori	2390.000	AV	29.2	26.7	6.5	32.4	-	30.0	53.9	23.9	
Hori	4804.000	AV	26.1	31.0	8.7	31.4	-	34.4	53.9	19.5	Floor noise
Hori	7206.000	AV	27.4	35.7	10.0	32.1	-	41.0	53.9	12.9	Floor noise
Hori	9608.000	AV	27.4	37.2	10.6	32.9	-	42.3	53.9	11.6	Floor noise
Vert	50.000	QP	41.0	10.8	7.6	32.1	-	27.3	40.0	12.7	
Vert	72.017	QP	35.5	6.2	7.9	32.1	-	17.5	40.0	22.5	
Vert	82.500	QP	35.5	7.2	8.1	32.1	-	18.7	40.0	21.3	
Vert	143.995	QP	34.4	14.6	8.7	32.0	-	25.7	43.5	17.8	
Vert	162.273	QP	35.4	15.6	8.8	32.0	-	27.8	43.5	15.7	
Vert	240.728	QP	33.5	11.6	9.5	31.9	-	22.7	46.0	23.3	
Vert	2390.000	PK	41.9	26.7	6.5	32.4	-	42.7	73.9	31.2	
Vert	4804.000	PK	38.3	31.0	8.7	31.4	-	46.6	73.9	27.3	Floor noise
Vert	7206.000	PK	41.2	35.7	10.0	32.1	-	54.8	73.9	19.1	
Vert	9608.000	PK	39.4	37.2	10.6	32.9	-	54.3	73.9	19.6	Floor noise
Vert	2390.000	AV	29.3	26.7	6.5	32.4	-	30.1	53.9	23.8	
Vert	4804.000	AV	26.1	31.0	8.7	31.4	-	34.4	53.9	19.5	Floor noise
Vert	7206.000	AV	31.0	35.7	10.0	32.1	-	44.6	53.9	9.3	
Vert	9608.000	AV	27.4	37.2	10.6	32.9	-	42.3	53.9	11.6	Floor noise

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter+Distance factor(above 1 GHz)) - Gain(Amplifier)

Distance factor: 1 GHz - 10 GHz 20log (4.3 m / 3.0 m) = 3.13 dB 10 GHz - 26.5 GHz 20log (1.0 m / 3.0 m) = -9.5 dB

20dBc Data Sheet

Polarity	Frequency	Detector	Reading	Ant	Loss	Gain	Result	Limit	Margin	Remark
				Factor						
	[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	
Hori	2402.000	PK	92.2	26.7	6.5	32.4	93.0	-	-	Carrier
Hori	2400.000	PK	37.6	26.7	6.5	32.4	38.4	73.0	34.6	
Vert	2402.000	PK	93.1	26.7	6.5	32.4	93.9	-	-	Carrier
Vert	2400.000	PK	38.2	26.7	6.5	32.4	39.0	73.9	34.9	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter+Distance factor(above 1 GHz)) - Gain(Amprifier)

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^{*}Other frequency noises omitted in this report were not seen or had enough margin (more than 20 dB).

^{*}These results have sufficient margin without taking account Dwell time factor.

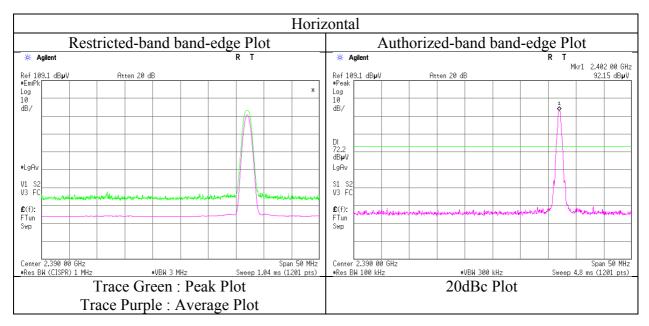
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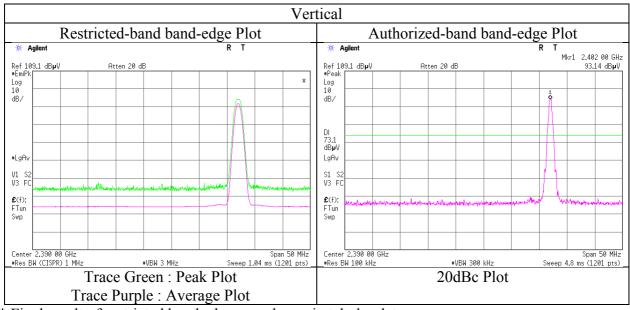
<u>Radiated Spurious Emission</u> (Reference Plot for band-edge)

Report No. 11624584H
Test place Ise EMC Lab.
Semi Anechoic Chamber No.3

Date April 17, 2017
Temperature / Humidity 21 deg. C / 59 % RH
Engineer Shuichi Ohyama
(1 GHz -10 GHz)

Mode Tx, Hopping Off, DH5 2402 MHz





^{*} Final result of restricted band edge was shown in tabular data.

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Radiated Spurious Emission

Report No. 11624584H Test place Ise EMC Lab.

Semi Anechoic Chamber No.3 No.4 No.4

Date April 17, 2017 April 22, 2017 April 23, 2017
Temperature / Humidity 21 deg. C / 59 % RH 21 deg. C / 41 % RH 19 deg. C / 37 % RH
Engineer Shuichi Ohyama Tomoki Matsui Tomoki Matsui (1 GHz -10 GHz) (Below 1 GHz) (Above 10 GHz)

Mode Tx, Hopping Off, DH5 2441 MHz

D-1it	F	D-44	D 4:	A 4 F	T	C-i-	Doto Footon	D14	T ::4	Manain	Dd-
Polarity	Frequency	Detector			Loss	Gain	Duty Factor	Result	Limit	Margin	Remark
	[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dB]	,	[dBuV/m]	[dB]	
Hori	64.230	`	35.4	6.8	7.8	32.1	-	17.9	40.0	22.1	
Hori	154.129	QP	35.7	15.2	8.7	32.0	-	27.6	43.5	15.9	
Hori	162.277	QP	36.0	15.6	8.8	32.0	-	28.4	43.5	15.1	
Hori	180.499	QP	32.4	16.3	9.0	32.0	-	25.7	43.5	17.8	
Hori	186.569	QP	32.3	16.3	9.0	32.0	-	25.6	43.5	17.9	
Hori	240.728	QP	39.4	11.6	9.5	31.9	-	28.6	46.0	17.4	
Hori	4882.000	PK	38.7	31.3	8.7	31.4	-	47.3	73.9	26.6	Floor noise
Hori	7323.000	PK	40.1	35.6	9.9	32.2	-	53.4	73.9	20.5	Floor noise
Hori	9764.000	PK	39.8	37.2	10.6	33.0	-	54.6	73.9	19.3	Floor noise
Hori	4882.000	AV	25.8	31.3	8.7	31.4	-	34.4	53.9	19.5	Floor noise
Hori	7323.000	AV	28.3	35.6	9.9	32.2	-	41.6	53.9	12.3	Floor noise
Hori	9764.000	AV	26.9	37.2	10.6	33.0	-	41.7	53.9	12.2	Floor noise
Vert	50.000	QP	41.0	10.8	7.6	32.1	-	27.3	40.0	12.7	
Vert	73.125	QP	35.5	6.2	7.9	32.1	-	17.5	40.0	22.5	
Vert	83.490	QP	35.2	7.3	8.1	32.1	-	18.5	40.0	21.5	
Vert	143.995	QP	34.2	14.6	8.7	32.0	-	25.5	43.5	18.0	
Vert	162.273	QP	35.3	15.6	8.8	32.0	-	27.7	43.5	15.8	
Vert	559.255	QP	24.1	18.5	11.4	32.1	-	21.9	46.0	24.1	
Vert	4882.000	PK	38.7	31.3	8.7	31.4	-	47.3	73.9	26.6	Floor noise
Vert	7323.000	PK	40.8	35.6	9.9	32.2	-	54.1	73.9	19.8	
Vert	9764.000	PK	39.8	37.2	10.6	33.0	-	54.6	73.9	19.3	Floor noise
Vert	4882.000	AV	25.8	31.3	8.7	31.4	-	34.4	53.9	19.5	Floor noise
Vert	7323.000	AV	29.8	35.6	9.9	32.2	-	43.1	53.9	10.8	
Vert	9764.000	AV	26.9	37.2	10.6	33.0	-	41.7	53.9	12.2	Floor noise

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter+Distance factor(above 1 GHz)) - Gain(Amplifier)

Distance factor: 1 GHz - 10 GHz \sim 20log (4.3 m / 3.0 m) = 3.13 dB 10 GHz - 26.5 GHz 20log (1.0 m / 3.0 m) = -9.5 dB

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

^{*}Other frequency noises omitted in this report were not seen or had enough margin (more than 20 dB).

 $^{{}^*}$ These results have sufficient margin without taking account Dwell time factor.

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Radiated Spurious Emission

Report No. 11624584H Test place Ise EMC Lab.

Semi Anechoic Chamber No.3 No.4 No.4

Date April 17, 2017 April 22, 2017 April 23, 2017
Temperature / Humidity 21 deg. C / 59 % RH 21 deg. C / 41 % RH 19 deg. C / 37 % RH
Engineer Shuichi Ohyama Tomoki Matsui Tomoki Matsui (1 GHz -10 GHz) (Below 1 GHz) (Above 10 GHz)

Mode Tx, Hopping Off, DH5 2480 MHz

Polarity	Frequency	Detector	Reading	Ant.Fac.	Loss	Gain	Duty Factor	Result	Limit	Margin	Remark
1 olding	[MHz]	Beteetor	[dBuV]	[dB/m]	[dB]	[dB]	[dB]		[dBuV/m]	[dB]	Teman.
Hori	64.230	QP	33.2	6.8	7.8	32.1	-	15.7	40.0	24.3	
Hori	158.211	QP	36.5	15.4	8.8	32.0	_	28.7	43.5	14.8	
Hori	162.277	QP	35.4	15.6	8.8	32.0	-	27.8	43.5	15.7	
Hori	178.473	QP	31.4	16.2	9.0	32.0	-	24.6	43.5	18.9	
Hori	186.569	QP	32.2	16.3	9.0	32.0	-	25.5	43.5	18.0	
Hori	240.728	QP	39.4	11.6	9.5	31.9	-	28.6	46.0	17.4	
Hori	2483.500	PK	44.3	26.8	6.6	32.4	-	45.3	73.9	28.6	
Hori	4960.000	PK	39.0	31.5	8.7	31.3	-	47.9	73.9	26.0	Floor noise
Hori	7440.000	PK	39.2	35.5	10.0	32.2	-	52.5	73.9	21.4	Floor noise
Hori	9920.000	PK	39.4	37.2	10.7	33.1	-	54.2	73.9	19.7	Floor noise
Hori	2483.500	AV	31.6	26.8	6.6	32.4	-	32.6	53.9	21.3	
Hori	4960.000	AV	26.2	31.5	8.7	31.3	-	35.1	53.9	18.8	Floor noise
Hori	7440.000	AV	27.3	35.5	10.0	32.2	-	40.6	53.9	13.3	Floor noise
Hori	9920.000	AV	26.7	37.2	10.7	33.1	-	41.5	53.9	12.4	Floor noise
Vert	50.000	QP	41.3	10.8	7.6	32.1	-	27.6	40.0	12.4	
Vert	68.652	QP	32.6	6.2	7.9	32.1	-	14.6	40.0	25.4	
Vert	82.892	QP	35.1	7.2	8.1	32.1	-	18.3	40.0	21.7	
Vert	143.995	QP	35.3	14.6	8.7	32.0	-	26.6	43.5	16.9	
Vert	162.273	QP	33.8	15.6	8.8	32.0	-	26.2	43.5	17.3	
Vert	408.840	QP	26.7	15.9	10.5	32.0	-	21.1	46.0	24.9	
Vert	2483.500	PK	44.4	26.8	6.6	32.4	-	45.4	73.9	28.5	
Vert	4960.000		39.4	31.5	8.7	31.3	-	48.3	73.9		Floor noise
Vert	7440.000	PK	40.4	35.5	10.0	32.2	-	53.7	73.9	20.2	
Vert	9920.000	PK	39.4	37.2	10.7	33.1	-	54.2	73.9	19.7	Floor noise
Vert	2483.500	AV	32.0	26.8	6.6	32.4	-	33.0	53.9	20.9	
Vert	4960.000		26.5	31.5	8.7	31.3	-	35.4	53.9	18.5	Floor noise
Vert	7440.000	AV	29.2	35.5	10.0	32.2	-	42.5	53.9	11.4	
Vert	9920.000	AV	26.7	37.2	10.7	33.1	-	41.5	53.9	12.4	Floor noise

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter+Distance factor(above 1 GHz)) - Gain(Amplifier)

Distance factor: 1 GHz - 10 GHz $20\log (4.3 \text{ m} / 3.0 \text{ m}) = 3.13 \text{ dB}$

10 GHz - 26.5 GHz 20log (1.0 m / 3.0 m) = -9.5 dB

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

^{*}Other frequency noises omitted in this report were not seen or had enough margin (more than 20 dB).

^{*}These results have sufficient margin without taking account Dwell time factor.

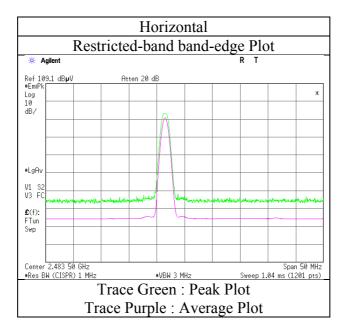
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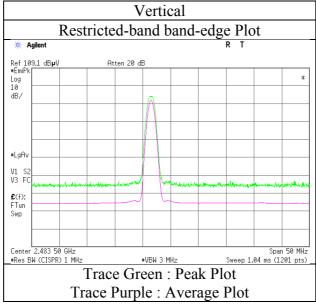
<u>Radiated Spurious Emission</u> (Reference Plot for band-edge)

Report No. 11624584H
Test place Ise EMC Lab.
Semi Anechoic Chamber No.3

Date April 17, 2017
Temperature / Humidity 21 deg. C / 59 % RH
Engineer Shuichi Ohyama
(1 GHz -10 GHz)

Mode Tx, Hopping Off, DH5 2480 MHz





^{*} Final result of restricted band edge was shown in tabular data.

UL Japan, Inc. Ise EMC Lab.

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Radiated Spurious Emission

Report No. 11624584H Test place Ise EMC Lab.

Semi Anechoic Chamber No.3 No.4 No.4

Date April 17, 2017 April 22, 2017 April 23, 2017
Temperature / Humidity 21 deg. C / 59 % RH 21 deg. C / 41 % RH 19 deg. C / 37 % RH
Engineer Shuichi Ohyama Tomoki Matsui Tomoki Matsui (1 GHz -10 GHz) (Below 1 GHz) (Above 10 GHz)

Mode Tx, Hopping Off, 3DH5 2402 MHz

Polarity	Frequency	Detector	Reading	Ant.Fac.	Loss	Gain	Duty Factor	Result	Limit	Margin	Remark
	[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dB]		[dBuV/m]	[dB]	
Hori	64.230	QP	35.4	6.8	7.8	32.1	-	17.9	40.0	22.1	
Hori	158.211	QP	36.5	15.4	8.8	32.0	-	28.7	43.5	14.8	
Hori	162.277	QP	36.6	15.6	8.8	32.0	-	29.0	43.5	14.5	
Hori	180.499	QP	32.1	16.3	9.0	32.0	-	25.4	43.5	18.1	
Hori	186.569	QP	32.3	16.3	9.0	32.0	-	25.6	43.5	17.9	
Hori	240.728	QP	39.4	11.6	9.5	31.9	-	28.6	46.0	17.4	
Hori	2390.000	PK	41.4	26.7	6.5	32.4	-	42.2	73.9	31.7	
Hori	4804.000	PK	39.5	31.0	8.7	31.4	-	47.8	73.9	26.1	Floor noise
Hori	7206.000	PK	39.9	35.7	10.0	32.1	-	53.5	73.9	20.4	Floor noise
Hori	9608.000	PK	39.5	37.2	10.6	32.9	-	54.4	73.9	19.5	Floor noise
Hori	2390.000	AV	28.7	26.7	6.5	32.4	-	29.5	53.9	24.4	
Hori	4804.000	AV	26.6	31.0	8.7	31.4	-	34.9	53.9	19.0	Floor noise
Hori	7206.000	AV	28.0	35.7	10.0	32.1	-	41.6	53.9	12.3	Floor noise
Hori	9608.000	AV	27.7	37.2	10.6	32.9	-	42.6	53.9	11.3	Floor noise
Vert	50.000	QP	41.0	10.8	7.6	32.1	-	27.3	40.0	12.7	
Vert	68.652	QP	35.4	6.2	7.9	32.1	-	17.4	40.0	22.6	
Vert	82.393	QP	35.5	7.1	8.1	32.1	-	18.6	40.0	21.4	
Vert	143.995	QP	34.4	14.6	8.7	32.0	-	25.7	43.5	17.8	
Vert	162.273	QP	35.1	15.6	8.8	32.0	-	27.5	43.5	16.0	
Vert	427.910	QP	26.5	16.3	10.7	32.0	-	21.5	46.0	24.5	
Vert	2390.000	PK	42.0	26.7	6.5	32.4	-	42.8	73.9	31.1	
Vert	4804.000	PK	38.8	31.0	8.7	31.4	-	47.1	73.9	26.8	Floor noise
Vert	7206.000	PK	40.1	35.7	10.0	32.1	-	53.7	73.9	20.2	Floor noise
Vert	9608.000	PK	39.8	37.2	10.6	32.9	-	54.7	73.9	19.2	Floor noise
Vert	2390.000	AV	28.8	26.7	6.5	32.4	-	29.6	53.9	24.3	
Vert	4804.000	AV	26.7	31.0	8.7	31.4	-	35.0	53.9	18.9	Floor noise
Vert	7206.000	AV	28.0	35.7	10.0	32.1	-	41.6	53.9	12.3	Floor noise
Vert	9608.000	AV	27.2	37.2	10.6	32.9	-	42.1	53.9	11.8	Floor noise

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter+Distance factor(above 1 GHz)) - Gain(Amplifier)

Distance factor: $1 \text{ GHz} - 10 \text{ GHz} \quad 20 \log (4.3 \text{ m} / 3.0 \text{ m}) = 3.13 \text{ dB}$

 $10 \text{ GHz} - 26.5 \text{ GHz} - 20 \log (4.5 \text{ m} / 3.6 \text{ m}) = -9.5 \text{ dB}$

*These results have sufficient margin without taking account Dwell time factor.

20dBc Data Sheet

requency	Detector	Reading	Ant	Loss	٥.				
				LUSS	Gain	Result	Limit	Margin	Remark
			Factor						
[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	
2402.000	PK	86.6	26.7	6.5	32.4	87.4	-	-	Carrier
2400.000	PK	36.0	26.7	6.5	32.4	36.8	67.4	30.6	
2402.000	PK	87.6	26.7	6.5	32.4	88.4	-	-	Carrier
2400.000	PK	36.8	26.7	6.5	32.4	37.6	68.4	30.8	
2	402.000 400.000 400.000 400.000	402.000 PK 400.000 PK 402.000 PK 400.000 PK	402.000 PK 86.6 400.000 PK 36.0 402.000 PK 87.6 400.000 PK 36.8	402.000 PK 86.6 26.7 400.000 PK 36.0 26.7 402.000 PK 87.6 26.7 400.000 PK 36.8 26.7	4402.000 PK 86.6 26.7 6.5 4400.000 PK 36.0 26.7 6.5 4402.000 PK 87.6 26.7 6.5 4402.000 PK 87.6 26.7 6.5 400.000 PK 36.8 26.7 6.5	402.000 PK 86.6 26.7 6.5 32.4 400.000 PK 36.0 26.7 6.5 32.4 402.000 PK 87.6 26.7 6.5 32.4 400.000 PK 36.8 26.7 6.5 32.4 400.000 PK 36.8 26.7 6.5 32.4	402.000 PK 86.6 26.7 6.5 32.4 87.4 400.000 PK 36.0 26.7 6.5 32.4 36.8 402.000 PK 87.6 26.7 6.5 32.4 88.4 400.000 PK 87.6 26.7 6.5 32.4 88.4 400.000 PK 36.8 26.7 6.5 32.4 37.6	402.000 PK 86.6 26.7 6.5 32.4 87.4 - 400.000 PK 36.0 26.7 6.5 32.4 36.8 67.4 402.000 PK 87.6 26.7 6.5 32.4 88.4 - 400.000 PK 36.8 26.7 6.5 32.4 37.6 68.4	402.000 PK 86.6 26.7 6.5 32.4 87.4 - - 400.000 PK 36.0 26.7 6.5 32.4 36.8 67.4 30.6 402.000 PK 87.6 26.7 6.5 32.4 88.4 - - 400.000 PK 36.8 26.7 6.5 32.4 37.6 68.4 30.8

 $Result = Reading + Ant \ Factor + Loss \ (Cable + Attenuator + Filter + Distance \ factor (above \ 1 \ GHz)) - Gain (Amprifier)$

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^{*}Other frequency noises omitted in this report were not seen or had enough margin (more than 20 dB).

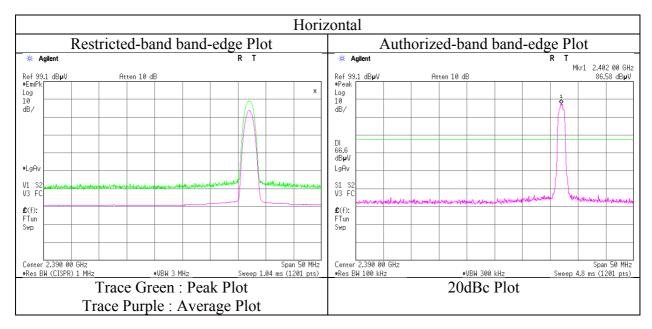
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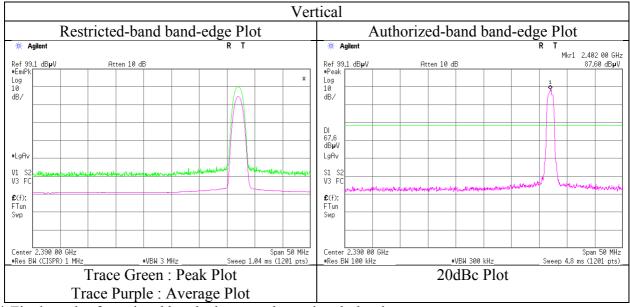
<u>Radiated Spurious Emission</u> (Reference Plot for band-edge)

Report No. 11624584H
Test place Ise EMC Lab.
Semi Anechoic Chamber No.3

Date April 17, 2017
Temperature / Humidity 21 deg. C / 59 % RH
Engineer Shuichi Ohyama
(1 GHz -10 GHz)

Mode Tx, Hopping Off, 3DH5 2402 MHz





^{*} Final result of restricted band edge was shown in tabular data.

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Radiated Spurious Emission

Report No. 11624584H Test place Ise EMC Lab.

Semi Anechoic Chamber No.3 No.4 No.4

Date April 17, 2017 April 22, 2017 April 23, 2017
Temperature / Humidity 21 deg. C / 59 % RH 21 deg. C / 41 % RH 19 deg. C / 37 % RH
Engineer Shuichi Ohyama Tomoki Matsui Tomoki Matsui (1 GHz -10 GHz) (Below 1 GHz) (Above 10 GHz)

Mode Tx, Hopping Off, 3DH5 2441 MHz

							•				
Polarity	Frequency	Detector			Loss	Gain	Duty Factor	Result	Limit	Margin	Remark
	[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	
Hori	64.230	QP	35.4	6.8	7.8	32.1	-	17.9	40.0	22.1	
Hori	158.211	QP	36.4	15.4	8.8	32.0	-	28.6	43.5	14.9	
Hori	162.277	QP	36.0	15.6	8.8	32.0	-	28.4	43.5	15.1	
Hori	178.473	QP	31.2	16.2	9.0	32.0	-	24.4	43.5	19.1	
Hori	186.569	QP	32.0	16.3	9.0	32.0	-	25.3	43.5	18.2	
Hori	240.728	QP	39.4	11.6	9.5	31.9	-	28.6	46.0	17.4	
Hori	4882.000	PK	38.8	31.3	8.7	31.4	-	47.4	73.9	26.5	Floor noise
Hori	7323.000	PK	40.5	35.6	9.9	32.2	-	53.8	73.9	20.1	Floor noise
Hori	9764.000	PK	40.0	37.2	10.6	33.0	-	54.8	73.9	19.1	Floor noise
Hori	4882.000	AV	26.0	31.3	8.7	31.4	-	34.6	53.9	19.3	Floor noise
Hori	7323.000	AV	27.8	35.6	9.9	32.2	-	41.1	53.9	12.8	Floor noise
Hori	9764.000	AV	26.4	37.2	10.6	33.0	-	41.2	53.9	12.7	Floor noise
Vert	50.000	QP	41.0	10.8	7.6	32.1	-	27.3	40.0	12.7	
Vert	68.652	QP	32.6	6.2	7.9	32.1	-	14.6	40.0	25.4	
Vert	82.233	QP	34.1	7.1	8.0	32.1	-	17.1	40.0	22.9	
Vert	143.995	QP	34.4	14.6	8.7	32.0	-	25.7	43.5	17.8	
Vert	162.273	QP	34.1	15.6	8.8	32.0	-	26.5	43.5	17.0	
Vert	558.517	QP	23.2	18.5	11.4	32.1	-	21.0	46.0	25.0	
Vert	4882.000	PK	38.8	31.3	8.7	31.4	-	47.4	73.9	26.5	Floor noise
Vert	7323.000	PK	40.2	35.6	9.9	32.2	-	53.5	73.9	20.4	Floor noise
Vert	9764.000	PK	40.2	37.2	10.6	33.0	-	55.0	73.9	18.9	Floor noise
Vert	4882.000	AV	25.9	31.3	8.7	31.4	-	34.5	53.9	19.4	Floor noise
Vert	7323.000	AV	28.0	35.6	9.9	32.2	-	41.3	53.9	12.6	Floor noise
Vert	9764.000	AV	26.8	37.2	10.6	33.0	-	41.6	53.9	12.3	Floor noise

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter+Distance factor(above 1 GHz)) - Gain(Amplifier)

Distance factor: 1 GHz - 10 GHz \sim 20log (4.3 m / 3.0 m) = 3.13 dB 10 GHz - 26.5 GHz 20log (1.0 m / 3.0 m) = -9.5 dB

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^{*}Other frequency noises omitted in this report were not seen or had enough margin (more than 20 dB).

 $^{{}^*}$ These results have sufficient margin without taking account Dwell time factor.

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Radiated Spurious Emission

Report No. 11624584H Test place Ise EMC Lab.

Semi Anechoic Chamber No.3 No.4 No.4

Date April 17, 2017 April 22, 2017 April 23, 2017
Temperature / Humidity 21 deg. C / 59 % RH 21 deg. C / 41 % RH 19 deg. C / 37 % RH
Engineer Shuichi Ohyama Tomoki Matsui Tomoki Matsui (1 GHz -10 GHz) (Below 1 GHz) (Above 10 GHz)

Mode Tx, Hopping Off, 3DH5 2480 MHz

B 1 2 1		l	n "		- 1	o :	ъ. т.	D 1			
Polarity	Frequency	Detector	Reading	Ant.Fac.	Loss	Gain	Duty Factor	Result	Limit	Margin	Remark
	[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dB]		[dBuV/m]	[dB]	
Hori	64.230	~	33.1	6.8	7.8	32.1	-	15.6	40.0	24.4	
Hori	158.211	`	36.5	15.4	8.8	32.0	-	28.7	43.5	14.8	
Hori	162.277	QP	35.4	15.6	8.8	32.0	-	27.8	43.5	15.7	
Hori	178.473	QP	31.1	16.2	9.0	32.0	-	24.3	43.5	19.2	
Hori	186.569	QP	31.5	16.3	9.0	32.0	-	24.8	43.5	18.7	
Hori	240.728	QP	39.4	11.6	9.5	31.9	-	28.6	46.0	17.4	
Hori	2483.500	PK	43.5	26.8	6.6	32.4	-	44.5	73.9	29.4	
Hori	4960.000	PK	39.1	31.5	8.7	31.3	-	48.0	73.9	25.9	Floor noise
Hori	7440.000	PK	40.1	35.5	10.0	32.2	-	53.4	73.9	20.5	Floor noise
Hori	9920.000	PK	41.2	37.2	10.7	33.1	-	56.0	73.9	17.9	Floor noise
Hori	2483.500	AV	30.1	26.8	6.6	32.4	-	31.1	53.9	22.8	
Hori	4960.000	AV	26.4	31.5	8.7	31.3	-	35.3	53.9	18.6	Floor noise
Hori	7440.000	AV	27.7	35.5	10.0	32.2	-	41.0	53.9	12.9	Floor noise
Hori	9920.000	AV	27.9	37.2	10.7	33.1	-	42.7	53.9	11.2	Floor noise
Vert	50.000	QP	41.3	10.8	7.6	32.1	-	27.6	40.0	12.4	
Vert	73.089	QP	33.5	6.2	7.9	32.1	-	15.5	40.0	24.5	
Vert	82.892	QP	35.1	7.2	8.1	32.1	-	18.3	40.0	21.7	
Vert	143.995	OP	35.3	14.6	8.7	32.0	-	26.6	43.5	16.9	
Vert	162.273	OP	33.4	15.6	8.8	32.0	-	25.8	43.5	17.7	
Vert	240.728	OP	33.1	11.6	9.5	31.9	-	22.3	46.0	23.7	
Vert	2483.500	PK	44.6	26.8	6.6	32.4	-	45.6	73.9	28.3	
Vert	4960.000		39.4	31.5	8.7	31.3	_	48.3	73.9	25.6	Floor noise
Vert	7440.000	PK	40.5	35.5	10.0	32.2	_	53.8	73.9		Floor noise
Vert	9920.000		40.6	37.2	10.7	33.1	_	55.4	73.9		Floor noise
Vert	2483.500	AV	30.5	26.8	6.6	32.4	-	31.5	53.9	22.4	
Vert	4960.000	AV	26.4	31.5	8.7	31.3	_	35.3	53.9	18.6	Floor noise
Vert	7440.000		27.6	35.5	10.0	32.2	_	40.9	53.9		Floor noise
Vert	9920.000		27.8	37.2	10.7	33.1	_	42.6	53.9		Floor noise

 $Result = Reading + Ant \ Factor + Loss \ (Cable + Attenuator + Filter + Distance \ factor (above \ 1 \ GHz)) - Gain (Amplifier)$

Distance factor: 1 GHz - 10 GHz $20 \log (4.3 \text{ m} / 3.0 \text{ m}) = 3.13 \text{ dB}$

 $10 \text{ GHz} - 26.5 \text{ GHz} \ 20 \log (1.0 \text{ m} / 3.0 \text{ m}) = -9.5 \text{ dB}$

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^{*}Other frequency noises omitted in this report were not seen or had enough margin (more than 20 dB).

^{*}These results have sufficient margin without taking account Dwell time factor.

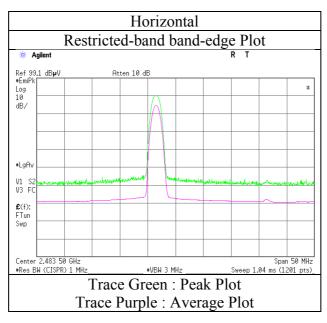
Test report No. : 11624584H-C
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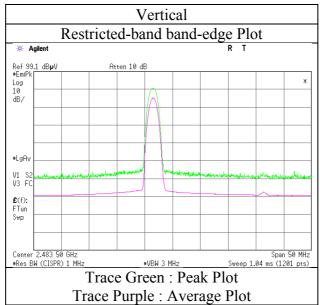
<u>Radiated Spurious Emission</u> (Reference Plot for band-edge)

Report No. 11624584H
Test place Ise EMC Lab.
Semi Anechoic Chamber No.3

Date April 17, 2017
Temperature / Humidity 21 deg. C / 59 % RH
Engineer Shuichi Ohyama
(1 GHz -10 GHz)

Mode Tx, Hopping Off, 3DH5 2480 MHz





^{*} Final result of restricted band edge was shown in tabular data.

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Radiated Spurious Emission (Plot data, Worst case)

Report No. 11624584H Test place Ise EMC Lab.

Semi Anechoic Chamber No.3 No.4 No.4

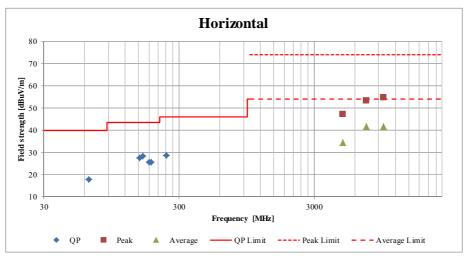
 Date
 April 17, 2017
 April 22, 2017
 April 23, 2017

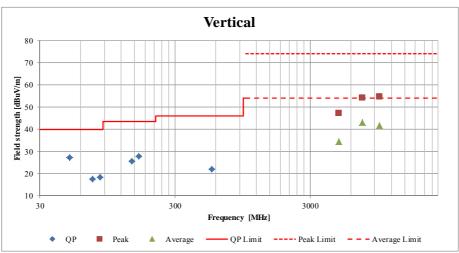
 Temperature / Humidity
 21 deg. C / 59 % RH
 21 deg. C / 41 % RH
 19 deg. C / 37 % RH

 Engineer
 Shuichi Ohyama
 Tomoki Matsui
 Tomoki Matsui

 (1 GHz -10 GHz)
 (Below 1 GHz)
 (Above 10 GHz)

Mode Tx, Hopping Off, DH5 2441 MHz





^{*}These plots data contains sufficient number to show the trend of characteristic features for EUT.

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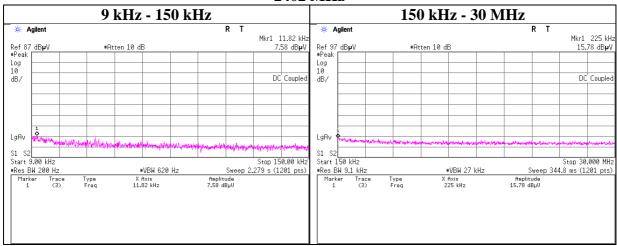
Test report No. : 11624584H-C
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Issued date : June 30, 2017
FCC ID : 2AL4MDMS-W1

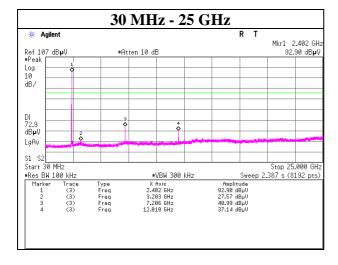
Conducted Spurious Emission

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date April 18, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping Off, DH5

2402 MHz





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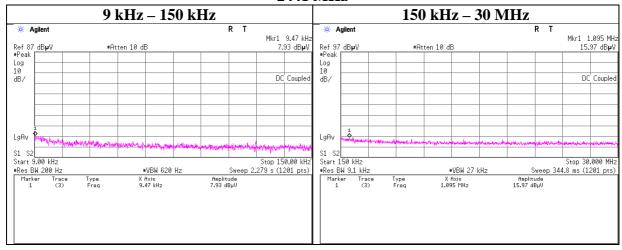
Test report No. : 11624584H-C
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FCC ID : 2AL4MDMS-W1

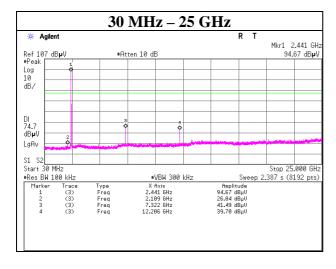
Conducted Spurious Emission

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date April 18, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping Off, DH5

2441 MHz





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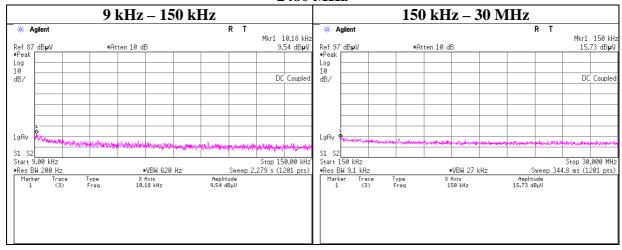
Test report No. : 11624584H-C
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Issued date : June 30, 2017
FCC ID : 2AL4MDMS-W1

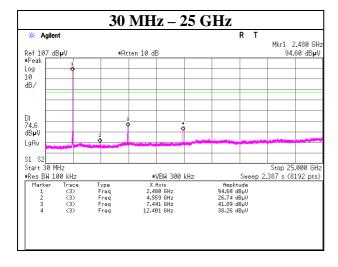
Conducted Spurious Emission

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date April 18, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping Off, DH5

2480 MHz





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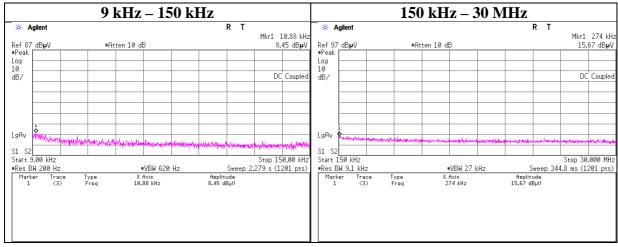
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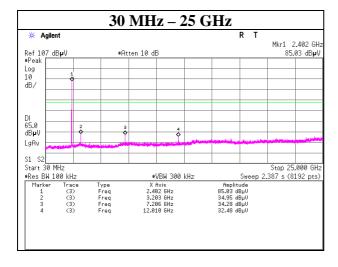
Conducted Spurious Emission

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date April 18, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping Off, 3DH5

2402 MHz





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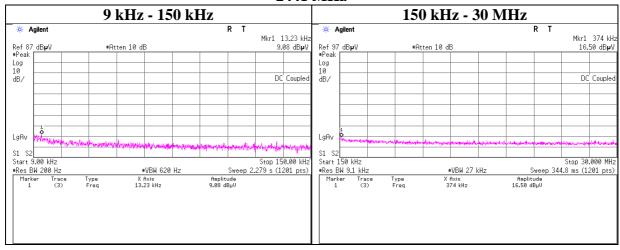
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FCC ID : 2AL4MDMS-W1

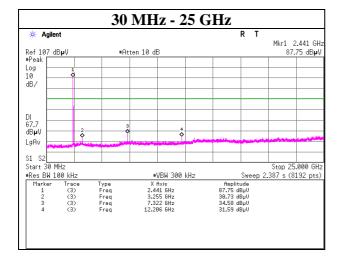
Conducted Spurious Emission

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date April 18, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping Off, 3DH5

2441 MHz





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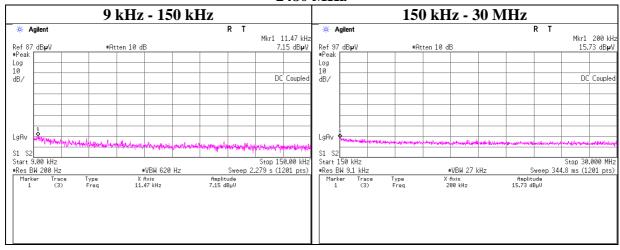
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FCC ID : 2AL4MDMS-W1

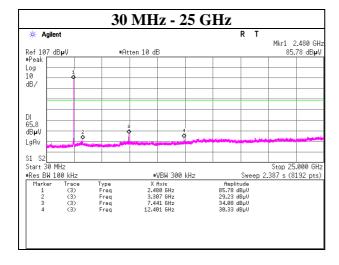
Conducted Spurious Emission

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date April 18, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx, Hopping Off, 3DH5

2480 MHz





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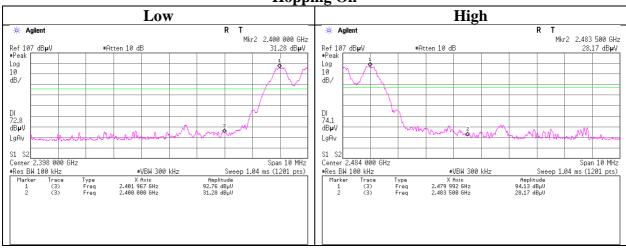
 FCC ID
 : 2AL4MDMS-W1

Conducted Emission Band Edge compliance

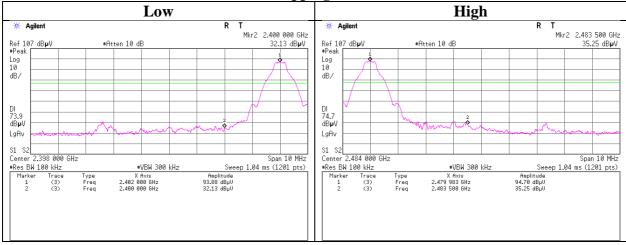
Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date May 8, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx DH5

Hopping On



Hopping Off



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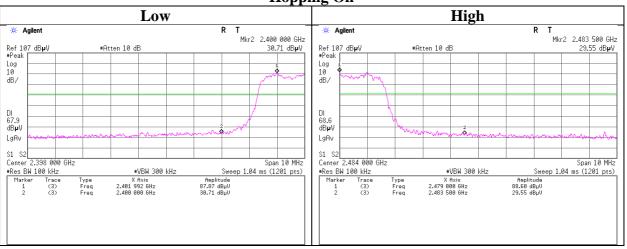
 FCC ID
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Conducted Emission Band Edge compliance

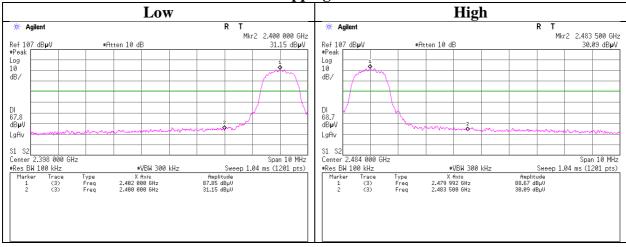
Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
Date May 8, 2017
Temperature / Humidity 24 deg. C / 41 % RH
Engineer Takumi Shimada
Mode Tx 3DH5

Hopping On



Hopping Off



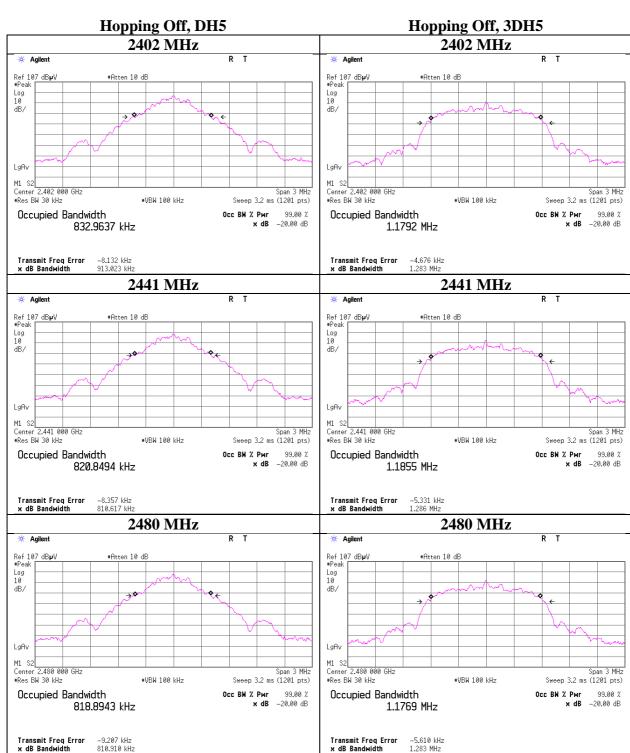
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99% Occupied Bandwidth

Test place Ise EMC Lab. No.6 Measurement Room

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Engineer Takumi Shimada
Mode Tx Hopping Off



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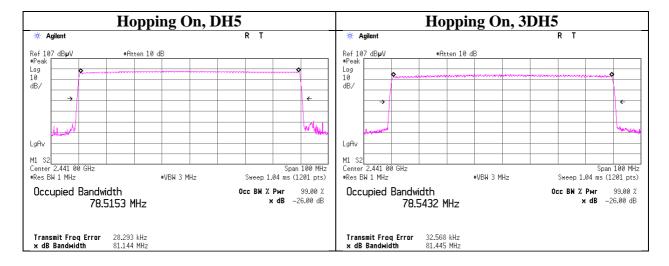
 Issued date
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99% Occupied Bandwidth

Test place Ise EMC Lab. No.6 Measurement Room

Report No. 11624584H
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APPENDIX 2: Test instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date Interval(month
MAEC-02	Semi Anechoic	TDK	Semi Anechoic	DA-06902	CE	2016/08/02 * 12
	Chamber(NSA)		Chamber 3m			
MOS-22	Thermo-Hygrometer	Custom	CTH-201	0003	CE	2016/12/13 * 12
MJM-14	Measure	KOMELON	KMC-36	-	CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	CE/RE	-
MSA-04	Spectrum Analyzer	Agilent	E4448A	US44300523	CE	2016/11/10 * 12
MTR-03	Test Receiver	Rohde & Schwarz	ESCI	100300	CE	2016/10/21 * 12
MLS-23	LISN(AMN)	Schwarzbeck	NSLK8127	8127-729	CE	2016/07/07 * 12
MCC-13	Coaxial Cable	Fujikura	3D-2W(12m)/ 5D-2W(5m)/ 5D-2W(0.8m)/	-	CE	2017/02/24 * 12
) (A T < 7	12 ID)	TEXT I I I	5D-2W(1m)		CIT.	2016/12/21 * 12
MAT-65	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2016/12/21 * 12
MMM-01	Digital Tester	Fluke	FLUKE 26-3	78030611	CE	2016/08/23 * 12
MPM-16	Power Meter	Agilent	8990B	MY51000271	AT	2016/04/07 * 12
MPSE-23	Power sensor	Agilent	N1923A	MY54070004	AT	2016/04/07 * 12
MAT-90	Attenuator	Weinschel Associates	WA56-10	56100306	AT	2016/06/09 * 12
MOS-29 MCC-66	Thermo-Hygrometer Microwave Cable 1G-40GHz	Custom Suhner	CTH-201 SUCOFLEX102	2901 28636/2	AT AT	2017/01/20 * 12 2017/04/04 * 12
MCC-64	Coaxial Cable	UL Japan		_	AT	2017/03/24 * 12
MAT-10	Attenuator(10dB)	Weinschel Corp	2	BL1173	AT	2016/11/28 * 12
MOS-14	Thermo-Hygrometer	Custom	CTH-201	1401	AT	2017/01/20 * 12
MAEC-03	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	RE	2016/10/20 * 12
MOS-13	Thermo-Hygrometer	Custom	CTH-180	1301	RE	2017/01/20 * 12
MJM-16	Measure	KOMELON	KMC-36	_	RE	-
MSA-16	Spectrum Analyzer	Agilent	E4440A	MY46186390	RE	2017/02/21 * 12
MHA-20	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	258	RE	2016/05/29 * 12
MCC-167	Microwave Cable	Junkosha	MWX221	1404S374(1m) / 1405S074(5m)	RE	2016/05/20 * 12
MPA-11	MicroWave System Amplifier	Agilent	83017A	MY39500779	RE	2017/03/21 * 12
MMM-08	DIGITAL HITESTER	Hioki	3805	051201197	RE	2017/01/19 * 12
MHF-25	High Pass Filter 3.5-18.0GHz	UL Japan	HPF SELECTOR	001	RE	2016/09/21 * 12
MAEC-04	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	RE	2016/10/19 * 12
MOS-15	Thermo-Hygrometer	Custom	CTH-180	1501	RE	2017/01/20 * 12
MJM-26	Measure	KOMELON	KMC-36	-	RE	-
MTR-10	EMI Test Receiver	Rohde & Schwarz	ESR26	101408	RE	2017/01/12 * 12
MBA-05	Biconical Antenna	Schwarzbeck	BBA9106	1302	RE	2016/11/23 * 12
MLA-23	Logperiodic Antenna(200-1000MHz)	Schwarzbeck	VUSLP9111B	911B-192	RE	2017/01/26 * 12
MCC-50	Coaxial Cable	UL Japan	- 0401 A	- MX/504/2202	RE	2016/06/20 * 12
MAT-97 MPA-14	Attenuator	KEYSIGHT	8491A	MY52462282	RE	2016/10/31 * 12
	Pre Amplifier	SONOMA INSTRUMENT	310	260833	RE	2017/03/27 * 12
MMM-10	DIGITAL HITESTER	Hioki	3805	051201148	RE	2017/01/19 * 12
MSA-10	Spectrum Analyzer	Agilent	E4448A	MY46180655	RE	2016/08/17 * 12
MHA-21 MCC-141	Horn Antenna 1-18GHz Microwave Cable	Schwarzbeck Junkosha	BBHA9120D MWX221	9120D-557 1305S002R(1m) / 1405S146(5m)	RE RE	2016/09/28 * 12 2016/06/21 * 12
MPA-12	MicroWave System Amplifier	Agilent	83017A	00650	RE	2016/10/21 * 12
MHA-17	Horn Antenna 15-40GHz	Schwarzbeck	BBHA9170	BBHA9170307	RE	2016/06/24 * 12
MHF-26	High Pass Filter	UL Japan	HPF SELECTOR	002	RE	2016/09/19 * 12
	3.5-18.0GHz					1

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*1) This test equipment was used for the tests before the expiration date of the calibration.

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item: CE: Conducted Emission test

RE: Radiated Emission test

AT: Antenna Terminal Conducted test

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